

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Cline *et al.*

Examiner: Chen, Eric Brice

Serial No.: 10/711,953

Art Unit: 1765

Filed: 10/15/2004

Docket No.: BUR920040122US1

Title: **DEEP TRENCH FORMATION IN SEMICONDUCTOR DEVICE FABRICATION**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INTERVIEW SUMMARY

Applicants' representative Khoi D. Nguyen asserts that the Examiner's Interview Summary (Form PTOL-413) mailed on 26 June 2006 accurately describes the substance of the June 20, 2006 telephonic interview between Applicants' representative Khoi D. Nguyen and Examiner Eric B. Chen.

Date: 06/30/2006

Jack P. Friedman

Jack P. Friedman Reg. No. 44,688 for
Khoi D. Nguyen reg. No. 47,820

Schmeiser, Olsen & Watts
22 Century Hill Drive, Suite 302
Latham, New York 12110
(518) 220-1850